

<b>Notice of References Cited</b>	Application/Control No. 10/762,479		Applicant(s)/Patent Under Reexamination KIM ET AL.	
	Examiner GOLAM MOWLA		Art Unit 1795	Page 1 of 1

#### U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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#### FOREIGN PATENT DOCUMENTS

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#### NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Mussy et al., "Characterisation and behaviour of Ti/TiO <sub>2</sub> /noble metal anodes", Electrochimica Acta, Volume 48, Issue 9, 20 April 2003, Pages 1131-1141.
	V	Macpherson et al., "Conducting-Atomic Force Microscopy Investigation of the Local Electrical Characteristics of a Ti/TiO <sub>2</sub> /Pt Anode", Electrochemical and Solid-State Letters, 4 (9) E33-E36 (2001).
	W	Avalle et al., "Characterization of TiO <sub>2</sub> films modified by platinum doping", Thin Solid Films, 210 (1992) 7-17.
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.